

IN THE CLAIMS

Please amend the claims as follows:

Claims 1-11 (Canceled).

Claim 12 (Currently Amended): In a probe device, an improved contact probe device including a plurality of contact probes, each contact probe comprising:

a film;

a plurality of wiring patterns formed on a first surface of the film, each wiring pattern having a front end portion projecting out from the first surface of the film in a direction parallel to the first surface of the film so as to form contact pins; and

a metal layer provided on a second surface of the film;

wherein the plurality of contact probes are arranged such that the axial lines of the contact pins are substantially vertical to a contact face of an object of measurement, and the plurality of contact probes are disposed in parallel so as to provide spaces between respective faces of the films of the plurality of contact probes, [[and]]

wherein the plurality of contact pins include a fabricated bending point at a middle portion in an axial line direction with a Ni plating treatment, and

wherein the fabricated bending point bends in an overdriving operation.

Claim 13 (Original): The probe device according to Claim 12, wherein a direction of bending of the contact pins of the plurality of the contact probes when a buckling load is applied is configured to be substantially constant.

Claims 14-20 (Canceled).